

# Bringing Insight into the Analysis of Relay Life-Test Failures.



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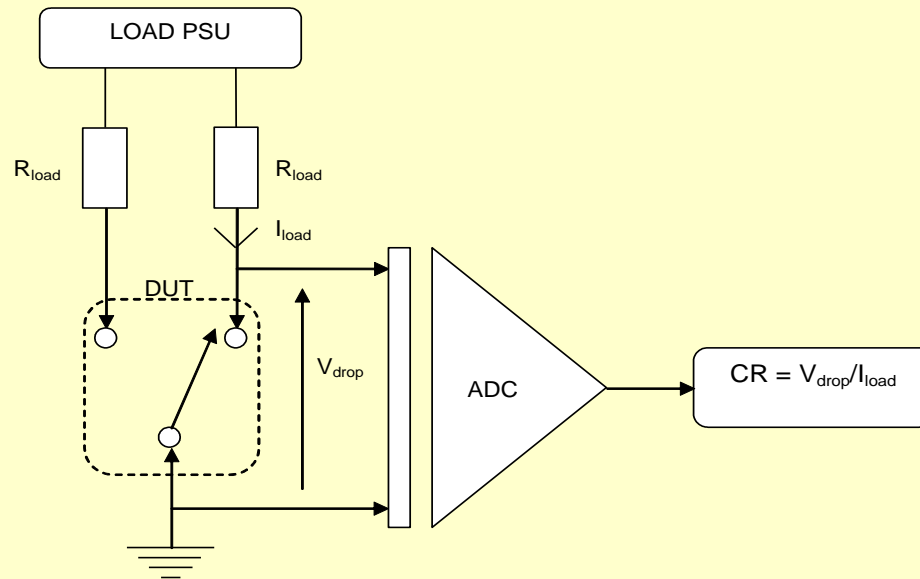
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# Life-Test Requirements

- To measure 'contact resistance' on a CLOSED contact.
- To confirm that at least 90/95% of the contact load voltage exists whilst the relay contact is OPEN.
- To perform measurements on a large number of contacts simultaneously at close to full relay device operating speeds.
- To isolate failure information and provide insight into the possible cause and progression of failures.

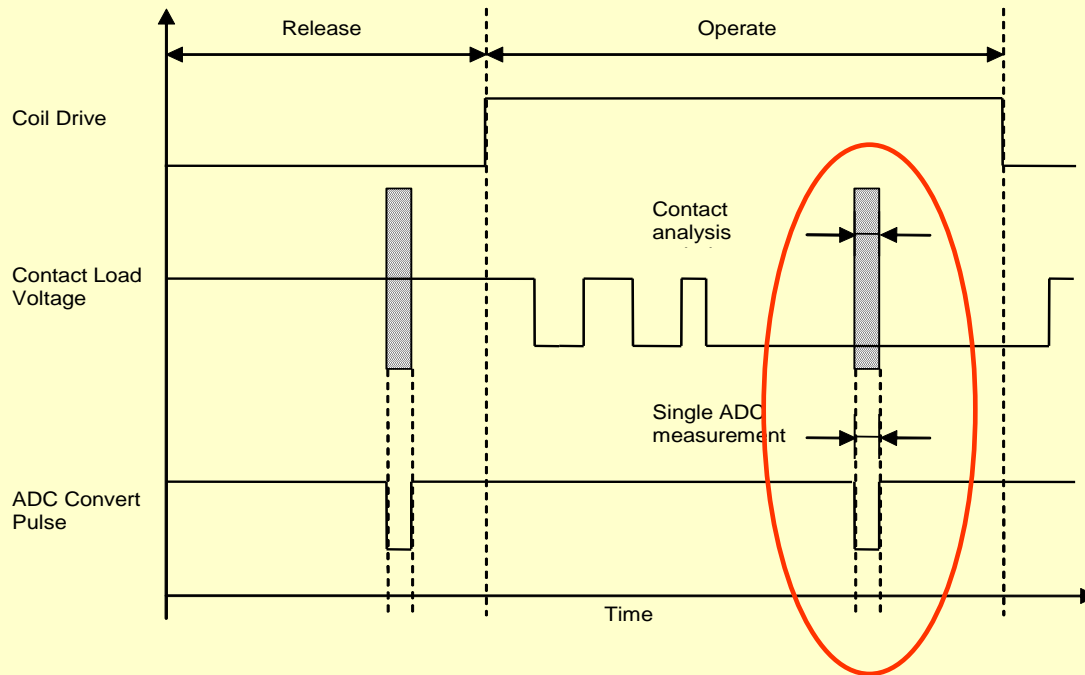
# Measuring Contact Resistance

- CR measurements normally achieved using an analogue to digital converter (ADC)



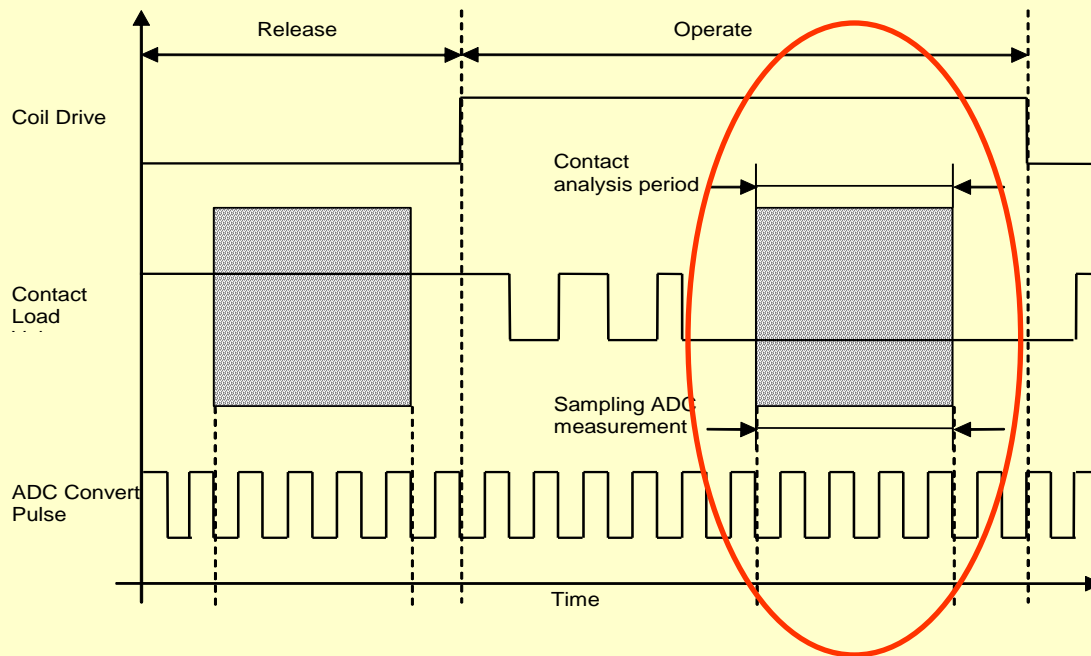
# Traditional Contact Resistance Measurement

- Single Sample ADC Measurements



# Bringing DSO techniques to life-testing

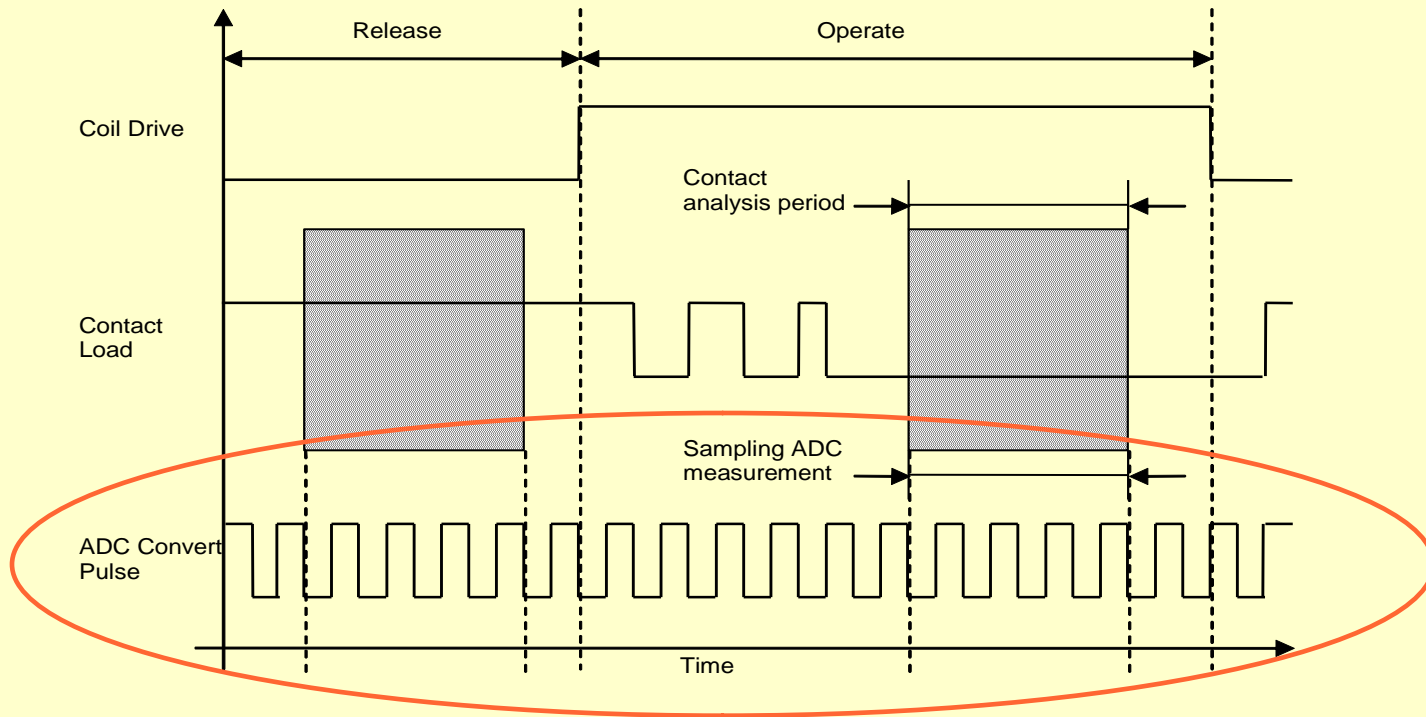
- Putting a digital storage oscilloscope behind each contact.



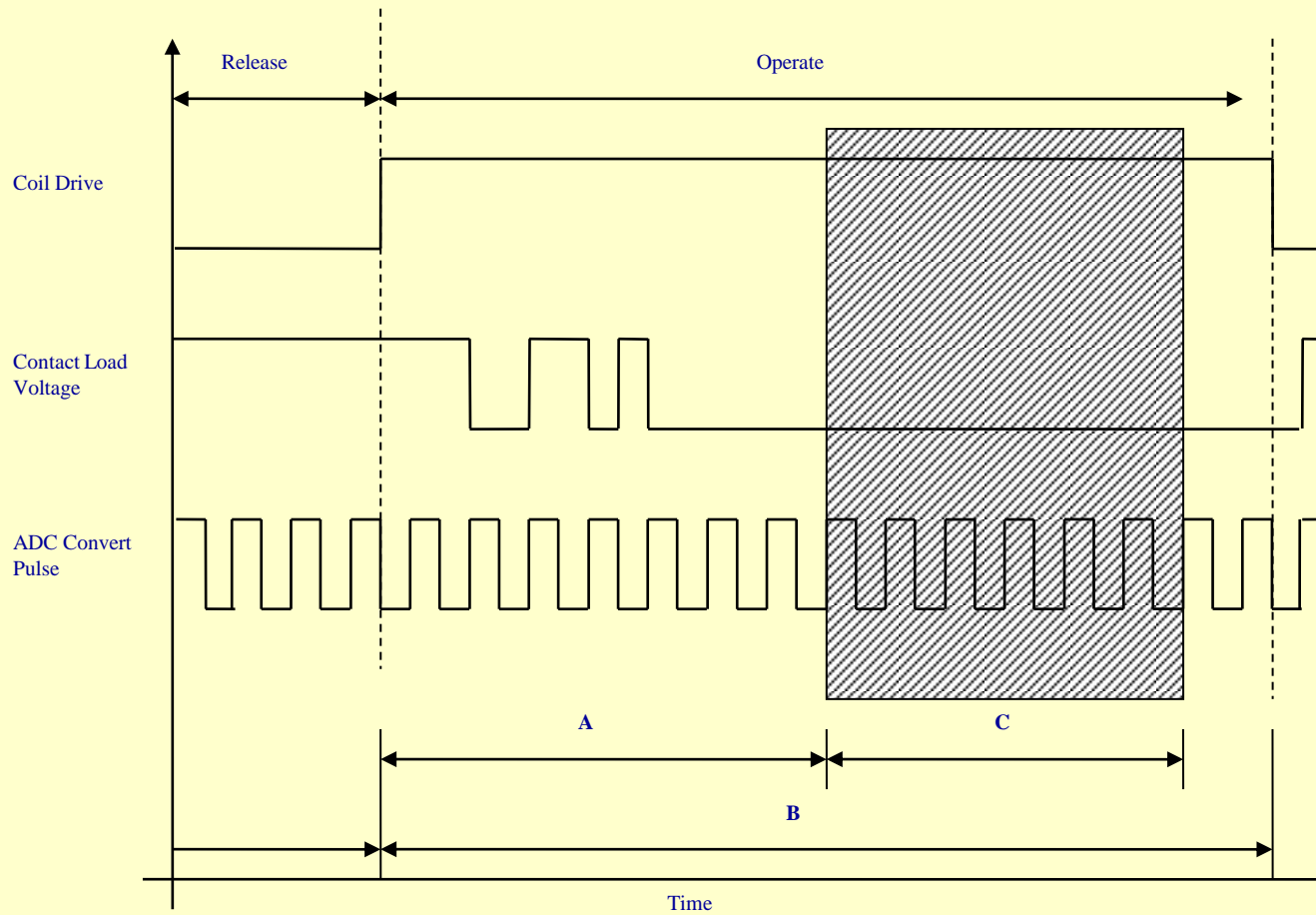
# Reflex 50 Design Aims

- To provide the user with greater insight into contact activity.
- To provide complete flexibility in setting up a CR measurement.
- To push device switching speeds in excess of 1 KHz over a variety of loads.

# Continuous sampling (DSO) retains the greatest information



# Complete flexibility in setting up a CR measurement

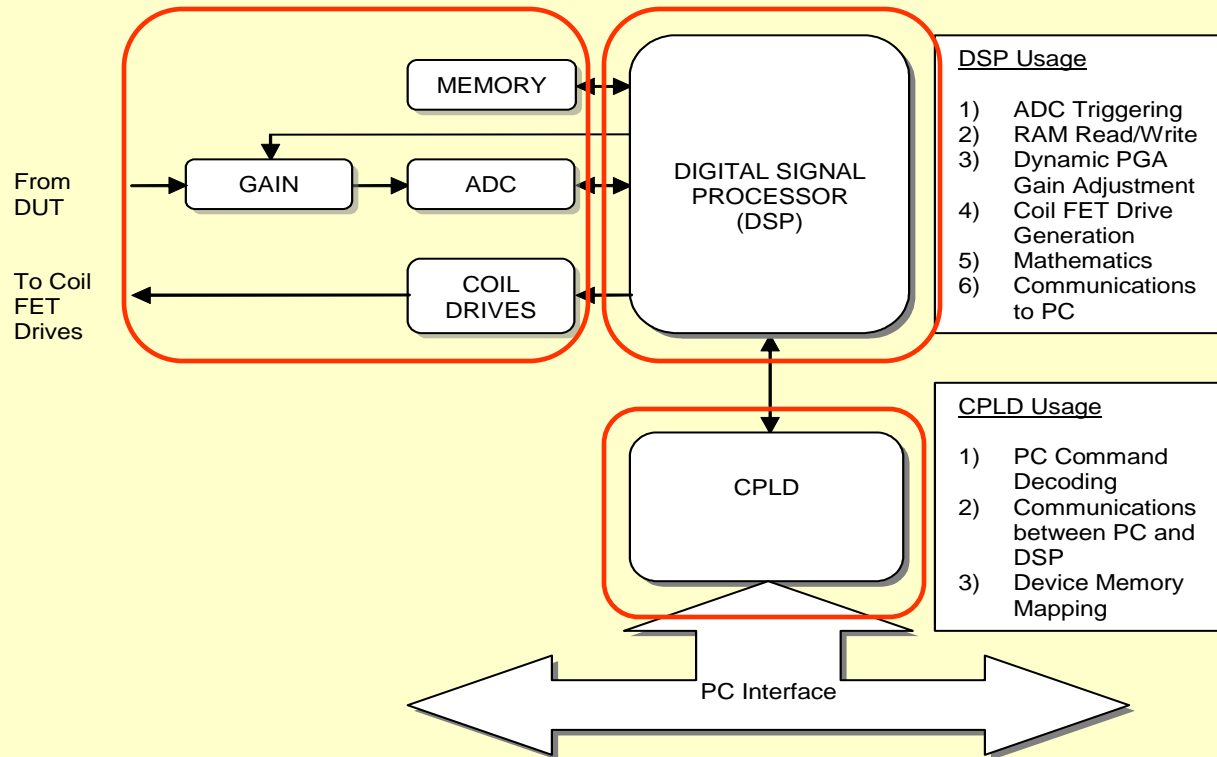




# How we push up device switching speeds.

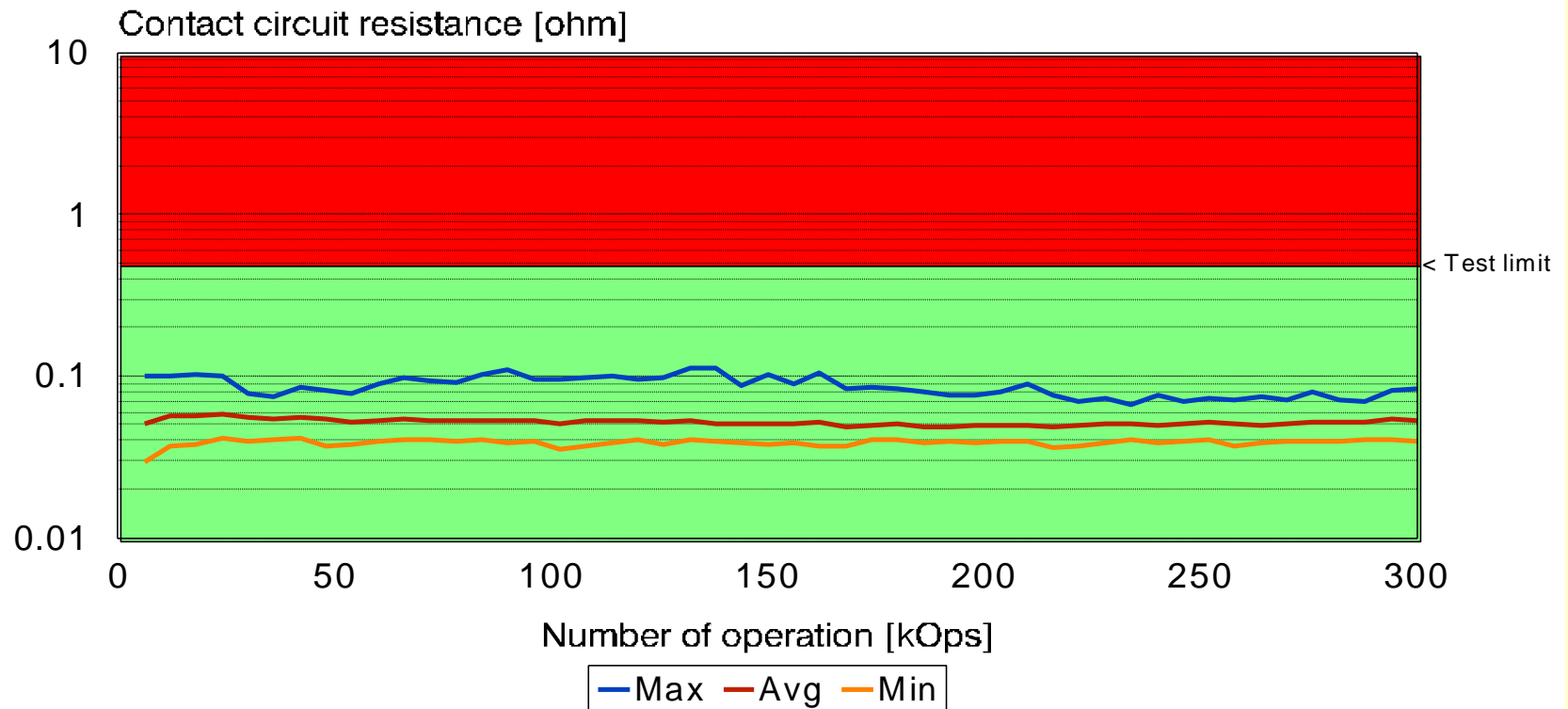
- Transfer time critical functions from software into hardware.
- Provide hardware with the computational power of a dedicated processor.
- Prevent data collation from interrupting time critical measurement procedures

# Measurement architecture behind each contact

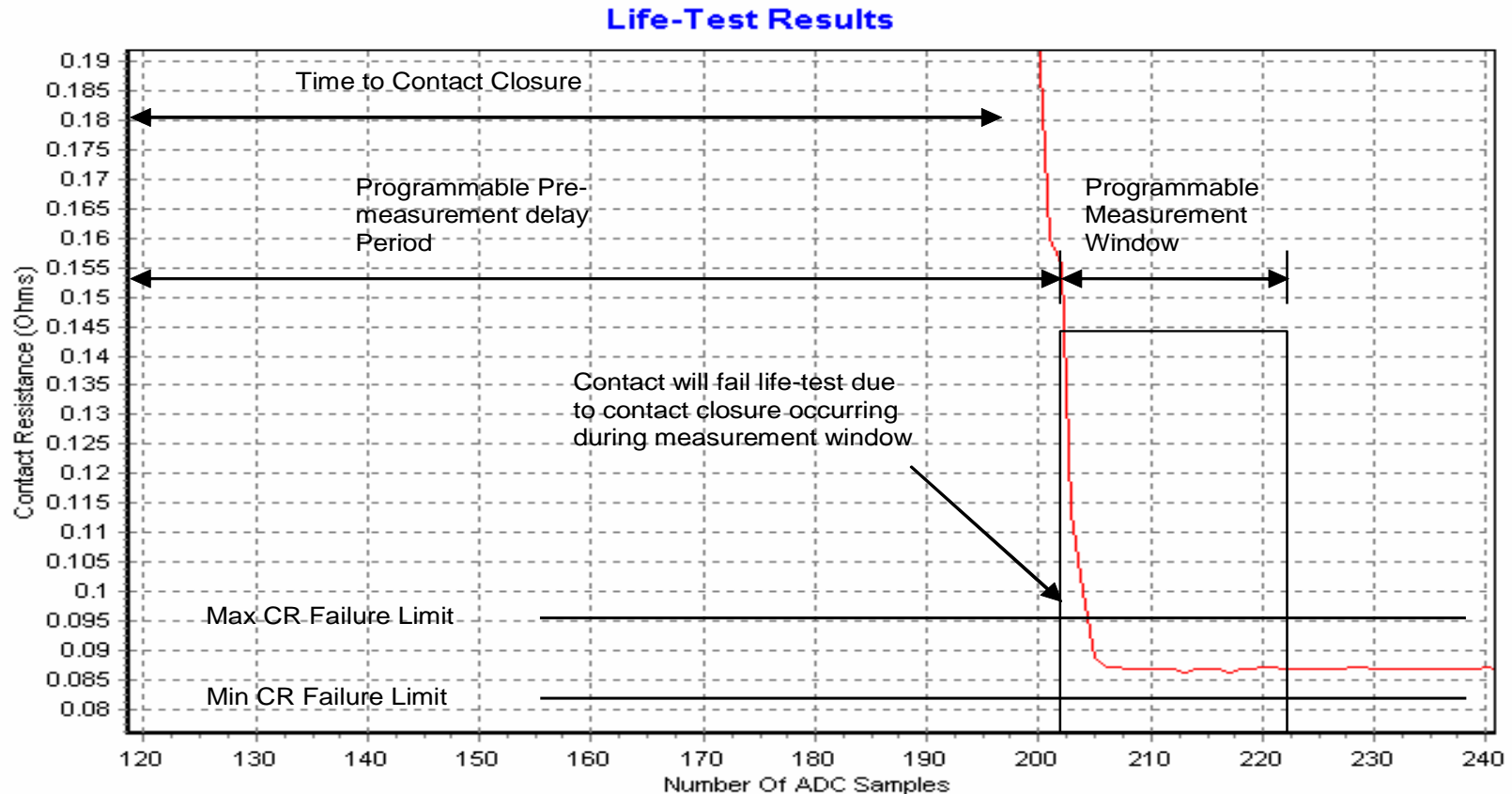


# Traditional results show only CR

## CCR Normally Closed Contacts



# With DSO we can separate timing and CR failures



Relay device cycled at 20Hz using a resistive load of 1V/10mA



# Conclusion

- The DSO solution separates timing and CR failures – a massive improvement in contact insight.
- The dedicated DSP processor behind each contact gives dramatic speed improvement.
- The above two techniques combine to permit complete flexibility in programming the CR test environment.